

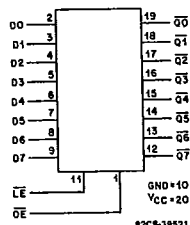
Octal Transparent Latch, 3-State Inverting

CD54AC563/3A
CD54ACT563/3A

T-46-07-11

The RCA CD54AC563/3A and CD54ACT563/3A are octal transparent 3-state latches that utilize the new RCA ADVANCED CMOS LOGIC technology. The outputs are transparent to the inputs when the Latch Enable (LE) is HIGH. When the Latch Enable (LE) goes LOW, the data is latched. The Output Enable (OE) controls the 3-state outputs. When the Output Enable (OE) is HIGH, the outputs are in the high-impedance state. The latch operation is independent of the state of the Output Enable.

The CD54AC563/3A and CD54ACT563/3A are supplied in 20-lead dual-in-line ceramic packages (F suffix).



Package Specifications

See Section 11, Fig. 13

FUNCTIONAL DIAGRAM & TERMINAL ASSIGNMENT

Static Electrical Characteristics (Limits with black dots (•) are tested 100%.)

CHARACTERISTICS	TEST CONDITIONS		V _{CC} (V)	AMBIENT TEMPERATURE (T _A) - °C				UNITS
				+25		-55 to +125		
	V _I (V)	I _O (mA)		MIN.	MAX.	MIN.	MAX.	
3-State Leakage Current I _{oz}	V _{IH} or V _{IL} V _O = V _{CC} or GND		5.5	—	±0.5•	—	±10•	μA
Quiescent Supply Current (MSI) I _{CC}	V _{CC} or GND	0	5.5	—	8•	—	160•	μA

The complete static electrical test specification consists of the above by-type static tests combined with the standard static tests in the beginning of this section.

ACT INPUT LOADING TABLE

INPUT	UNIT LOAD*
OE	0.87
Dn	0.5
LE	0.8

*Unit load is ΔI_{CC} limit specified in Static Characteristics Chart, e.g., 2.4 mA max. @ 25°C.

Burn-In Test-Circuit Connections (Use Static II for /3A burn-in and Dynamic for Life Test.)

Static	STATIC BURN-IN I			STATIC BURN-IN II		
	OPEN	GROUND	V _{CC} (6V)	OPEN	GROUND	V _{CC} (6V)
CD54AC/ACT563	12-19	1-11	20	12-19	10	1-9,11,20
Dynamic	OPEN	GROUND	1/2 V _{CC} (3V)	V _{CC} (6V)	OSCILLATOR	
	—	1,10	12-19	20	50 kHz	25 kHz
CD54AC/ACT563	—	1,10	12-19	20	11	2-9

NOTE: Each pin except V_{CC} and Gnd will have a resistor of 2k-47k ohms.

CD54AC563/3A

CD54ACT563/3A

SWITCHING CHARACTERISTICS: AC Series; $t_r, t_f = 3 \text{ ns}$, $C_L = 50 \text{ pF}$ (Worst Case)

CHARACTERISTICS	SYMBOL	V_{CC} (V)	-55 to +125°C		UNITS
			MIN.	MAX.	
Propagation Delays: Data to Qn	t_{PLH} t_{PHL}	1.5 3.3* 5†	— 2.9 1.9	140 20 11.3•	ns
$\overline{LE}$ on Qn	t_{PLH} t_{PHL}	1.5 3.3 5	— 3.4 2.2	164 23 13.1•	ns
Output Enable and Disable Times	t_{PZL} t_{PZH} t_{PLZ} t_{PHZ}	1.5 3.3 5	— 4.1 2.6	181 25.3 14.5•	ns
Power Dissipation Capacitance	$C_{PD}\S$	—	90 Typ.		pF
Min. (Valley) V_{OH} During Switching of Other Outputs (Output Under Test Not Switching)	V_{OHV}	5	4 Typ. @ 25°C		V
Max. (Peak) V_{OL} During Switching of Other Outputs (Output Under Test Not Switching)	V_{OLP}	5	1 Typ. @ 25°C		V
Input Capacitance	C_i	—	—	10	pF
3-State Output Capacitance	C_o	—	—	15	pF

SWITCHING CHARACTERISTICS: ACT Series; $t_r, t_f = 3 \text{ ns}$, $C_L = 50 \text{ pF}$ (Worst Case)

CHARACTERISTICS	SYMBOL	V_{CC} (V)	-55 to +125°C		UNITS
			MIN.	MAX.	
Propagation Delays Data to Qn	t_{PLH} t_{PHL}	5†	1.8	12.7•	ns
$\overline{LE}$ to Qn	t_{PLH} t_{PHL}	5	2.6	14.5•	ns
Output Enable and Disable Times	t_{PZL} t_{PZH} t_{PLZ} t_{PHZ}	5	2.6	14.5•	ns
Power Dissipation Capacitance	$C_{PD}\S$	—	108 Typ.		pF
Min. (Valley) V_{OH} During Switching of Other Outputs (Output Under Test Not Switching)	V_{OHV}	5	4 Typ. @ 25°C		V
Max. (Peak) V_{OL} During Switching of Other Outputs (Output Under Test Not Switching)	V_{OLP}	5	1 Typ. @ 25°C		V
Input Capacitance	C_i	—	—	10	pF
3-State Output Capacitance	C_o	—	—	15	pF

*3.3 V: min. is @ 3.6 V
max. is @ 3 V

†5 V: min. is @ 5.5 V
max. is @ 4.5 V

§ C_{PD} is used to determine the dynamic power consumption per latch.For AC, $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$ For ACT, $P_D = V_{CC}^2 f_i (C_{PD} + C_L) + V_{CC}\Delta I_{CC}$ where f_i = input frequency
 C_L = output load capacitance
 V_{CC} = supply voltage

(Limits with black dots (•) are tested 100%.)